



## LOW-POWER RS-485 FULL-DUPLEX DRIVERS/RECEIVERS

#### **FEATURES**

- Low Quiescent Power
  - 375 μA (Typical) Enabled Mode
  - 2 nA (Typical) Shutdown Mode
- **Small MSOP Package**
- 1/8 Unit-Load—Up to 256 Nodes per Bus
- 16 kV Bus-Pin ESD Protection, 6 kV All Pins
- Failsafe Receiver (Bus Open, Short, Idle)
- **TIA/EIA-485A Standard Compliant**
- **RS-422 Compatible**

#### **APPLICATIONS**

- **Motion Controllers**
- Point-of-Sale (POS) Terminals
- **Rack-to-Rack Communications**
- **Industrial Networks**
- **Power Inverters**
- **Battery-Powered Applications**
- **Building Automation**

## SN65HVD308xE (TOP VIEW) RF DE GND

DEVICE	SIGNAL RATE
SN65HVD3080E	200 kbps
SN65HVD3083E	1 Mbps
SN65HVD3086E	20 Mbps

#### DESCRIPTION

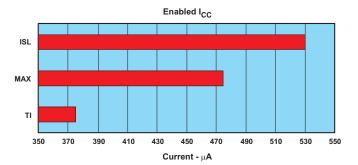
Each of these devices is a balanced driver and receiver designed for full-duplex RS-485 or RS-422 data bus networks. Powered by a 5-V supply, they are fully compliant with the TIA/EIA-485A standard.

With controlled bus output transition times, the devices are suitable for signaling rates from 200 kbps to 20 Mbps.

The devices are designed to operate with a low supply current, less than 1 mA (typical), exclusive of the load. When in the inactive shutdown mode, the supply current drops to a few nanoamps, making these devices ideal for power-sensitive applications.

The wide common-mode range and high ESD protection levels of these devices make them suitable for demanding applications such as motion controllers, electrical inverters, industrial networks, and cabled chassis interconnects where noise tolerance is essential.

These devices are characterized for operation over the temperature range -40°C to 85°C



 $\Delta$ 

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

#### SLLS771B-NOVEMBER 2006-REVISED MARCH 2007





This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### ORDERING INFORMATION

PART NUMBER	PACKAGE <sup>(1)</sup>	MARKED AS
SN65HVD3080E		ВТТ
SN65HVD3083E	DGS, DGSR (2)	BTU
SN65HVD3086E		BTF

<sup>(1)</sup> For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.

#### ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range unless otherwise noted (1)

		UNIT
V <sub>cc</sub>	Supply voltage range (2)	-0.3 V to 7 V
V <sub>(A)</sub> , V <sub>(B)</sub> , V <sub>(Y)</sub> , V <sub>(Z)</sub>	Voltage range at any bus terminal (A, B, Y, Z)	–9 V to 14 V
V <sub>(TRANS)</sub>	Voltage input, transient pulse through 100 $\Omega$ . See Figure 10 (A, B, Y, Z)	–50 to 50 V
VI	Input voltage range (D, DE, RE)	-0.3 V to V <sub>CC</sub> +0.3 V
$P_{D}$	Continuous total power dissipation	See the dissipation rating table
$T_J$	Junction temperature	170°C

<sup>(1)</sup> Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### **POWER DISSIPATION RATINGS**

PACKAGE	$T_A < 25^{\circ}C$ DERATING FACTOR <sup>(1)</sup> ABOVE $T_A < 25^{\circ}C$		T <sub>A</sub> = 85°C	
DGS-10	463 mW	3.71 mW/°C	241 mW	

<sup>(1)</sup> This is the inverse of the junction-to-ambient thermal resistance when board-mounted and with no air flow.

#### **ELECTROSTATIC DISCHARGE PROTECTION**

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Human Body Model <sup>(1)</sup>	A,B,Y,Z, and GND		16k		V
	All pins		6k		V
Field-induced-Charged Device Mode (2)	All pins		1.5k		V
Machine Model			200		<b>V</b>

Tested in accordance JEDEC Standard 22, Test Method A114-A. Bus pin stressed with respect to a common connection of GND and V<sub>CC</sub>.

<sup>(2)</sup> The R suffix indicated tape and reel.

<sup>(2)</sup> All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.

<sup>(2)</sup> Tested in accordance JEDEC Standard 22, Test Method C101.



#### **SUPPLY CURRENT**

over recommended operating conditions unless otherwise noted

		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
		RE at 0 V, D and DE at V <sub>CC,</sub> No load	Receiver enabled, Driver enabled		375	750	μΑ
	RE at 0 V, D and DE at 0 V, No load	Receiver enabled, Driver disabled		300	680	μΑ	
ICC	Supply current	$\overline{\text{RE}}$ at $\text{V}_{\text{CC}},$ D and DE at $\text{V}_{\text{CC}},$ No load	Receiver disabled, Driver enabled		240	600	μΑ
		RE at V <sub>CC</sub> , D and DE at 0 V, No load	Receiver disabled, Driver disabled		2	1000	nA

#### **RECOMMENDED OPERATING CONDITIONS**

over operating free-air temperature range unless otherwise noted

			MIN	NOM	MAX	UNIT
V <sub>CC</sub>	Supply voltage		4.5	5	5.5	٧
V <sub>I</sub> or V <sub>IC</sub>	Voltage at any bus terminal (	separately or common mode)	-7 <sup>(1)</sup>		12	V
V <sub>IH</sub>	High-level input voltage	D, DE, RE	2		$V_{CC}$	
V <sub>IL</sub>	Low-level input voltage	D, DE, RE	0		8.0	V
$V_{ID}$	Differential input voltage		-12		12	
	High lovel output ourrent	Driver	-60			A
I <sub>OH</sub>	High-level output current	Receiver	-10			mA
	Lour lovel output ourrent	Driver			60	A
I <sub>OL</sub>	Low-level output current	Receiver			10	mA
TJ	Junction temperature				150	°C
T <sub>A</sub>	Ambient still-air temperature		-40		85	-0

<sup>(1)</sup> The algebraic convention, in which the least positive (most negative) limit is designated as minimum is used in this data sheet.



#### **DRIVER ELECTRICAL CHARACTERISTICS**

over recommended operating conditions unless otherwise noted

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
		No load, I <sub>O</sub> = 0	3	4.3	V <sub>CC</sub>	
177 1	Differential autout valtees	$R_L = 54 \Omega$ , See Figure 1	1.5	2.3		V
V <sub>OD</sub>	Differential output voltage	V <sub>test</sub> = -7 V to 12 V, See Figure 2	1.5			V
		$R_L = 100 \Omega$ , See Figure 1	2			
$\Delta  V_{OD} $	Change in magnitude of differential output voltage	$R_L$ = 54 $\Omega$ , See Figure 1 and Figure 2	-0.2	0	0.2	V
V <sub>OC(SS)</sub>	Steady-state common-mode output voltage		1	2.6	3	
$\Delta V_{OC(SS)}$	Common-mode output voltage (Dominant)	See Figure 3	-0.1	0	0.1	V
V <sub>OC(PP)</sub>	Peak-to-peak common-mode output voltage			0.5		
		$V_{CC} = 0 \text{ V}, V_{(Z)} \text{ or } V_{(Y)} = 12 \text{ V}$ Other input at 0 V			1	
I <sub>Z(Y)</sub> or		$V_{CC} = 0 \text{ V}, V_{(Z)} \text{ or } V_{(Y)} = -7 \text{ V}$ Other input at 0 V	-1			
$I_{Z(Z)}$	High-impedance state output current	$V_{CC} = 5 \text{ V}, V_{(Z)} \text{ or } V_{(Y)} = 12 \text{ V}$ Other input at 0 V			1	μA
		$V_{CC} = 5 \text{ V}, V_{(Z)} \text{ or } V_{(Y)} = -7 \text{ V}$ Other input at 0 V	-1			
I <sub>I</sub>	Input current	D, DE	-100		100	μΑ
Ios	Short-circuit output current	-7 V ≤ V <sub>O</sub> ≤ 12 V	-250		250	mA

#### **DRIVER SWITCHING CHARACTERISTICS**

over recommended operating conditions unless otherwise noted

	PARAMETER <sup>(1)</sup>		TEST CONDITIONS	MIN	TYP	MAX	UNIT
		HVD3080E				1.3	μs
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay time, low-to-high-level output Propagation delay time, high-to-low-level output	HVD3083E			150	500	ns
PHL	Tropagation delay time, high to low level output	HVD3086E			12	20	ns
		HVD3080E	$R_L = 54 \Omega$ ,	0.5	0.9	1.5	μs
t <sub>r</sub> , t <sub>f</sub>	Differential output signal rise time Differential output signal fall time	HVD3083E	$C_{L} = 50 \text{ pF},$		200	300	ns
4	Smorthan culput digital fail time	HVD3086E	See Figure 4		7	15	ns
		HVD3080E			20	200	ns
t <sub>sk(p)</sub>	Pulse skew ( t <sub>PHL</sub> - t <sub>PLH</sub>  )	HVD3083E			5	50	ns
		HVD3086E			1.4	5	ns
	Propagation delay time, high-impedance-to-high-level output	HVD3080E			2.5	7	μs
$t_{PZH}$		HVD3083E	$R_L = 110 \Omega$ , $\overline{RE}$ at 0 V,		1	2.5	μs
		HVD3086E			13	30	ns
		HVD3080E	See Figure 5		80	200	ns
$t_{\text{PHZ}}$	Propagation delay time, high-level-to-high-impedance output	HVD3083E			60	100	ns
	ingi iovorio ingi impodance caipat	HVD3086E			12	30	ns
		HVD3080E			2.5	7	μs
$t_{\text{PZL}}$	Propagation delay time, high-impedance-to-low-level output	HVD3083E			1	2.5	μs
		HVD3086E	$R_L = 110 \Omega,$ RE at 0 V,		13	30	ns
		HVD3080E	See Figure 6		80	200	ns
$t_{\text{PLZ}}$	Propagation delay time, low-level-to-high-impedance output	HVD3083E			60	100	ns
		HVD3086E			12	30	ns
t <sub>PZH</sub> ,	Propagation delay time, standby-to-high-level output (S	See Figure 5)	$R_1 = 110 \Omega$ , $\overline{RE}$ at 3 V		3.5	7	
$t_{PZL}$	Propagation delay time, standby-to-low-level output (Se	ee Figure 6)	KL = 110 22, RE at 3 V		3.5	′	μs

<sup>(1)</sup> SNHVD3080 and SNHVD3083 are in the *Product Preview* state of development.

SN65HVD3080E



#### RECEIVER ELECTRICAL CHARACTERISTICS

over recommended operating conditions unless otherwise noted

	PARAMETEI	२	TEST CONDITIONS	MIN	TYP <sup>(1)</sup>	MAX	UNIT
$V_{IT+}$	Positive-going differential i	nput threshold voltage	$I_O = -10 \text{ mA}$		-0.08	-0.01	
V <sub>IT-</sub>	Negative-going differential voltage	input threshold	I <sub>O</sub> = 10 mA	-0.2	-0.1		V
$V_{\text{hys}}$	Hysteresis voltage (V <sub>IT+</sub> - '	V <sub>IT-</sub> )			30		mV
V <sub>OH</sub>	High-level output voltage		$V_{ID}$ = 200 mV, $I_{OH}$ = -10 mA, See Figure 7 and Figure 8	4	4.6		V
V <sub>OL</sub>	OL Low-level output voltage		$V_{ID}$ = -200 mV, $I_{OH}$ = 10 mA, See Figure 7 and Figure 8		0.15	0.4	V
$I_{OZ}$	High-impedance-state outp	out current	$V_O = 0$ or $V_{CC}$	-1		1	μA
			$V_A$ or $V_B = 12 \text{ V}$		0.04	0.11	
	Due input ourrent	0.1	$V_A$ or $V_B = 12 \text{ V}$ , $V_{CC} = 0 \text{ V}$		0.06	0.13	mA
11	Bus input current	Other input at 0V	$V_A$ or $V_B = -7 V$	-0.1	-0.04		mA
			$V_A$ or $V_B = -7 V$ , $V_{CC} = 0 V$	-0.05	-0.03		
I <sub>IH</sub>	High-level input current		V <sub>IH</sub> = 2 V	-60	-30		μΑ
$I_{\rm IL}$	Low-level input current		V <sub>IL</sub> = 0.8 V	-60	-30		μΑ
$C_{ID}$	Differential input capacitan	ice	$V_I = 0.4 \sin (4E6\pi t) + 0.5 V$		7		pF

<sup>(1)</sup> All typical values are at 25°C and with a 3.3-V supply.

#### RECEIVER SWITCHING CHARACTERISTICS

over recommended operating conditions unless otherwise noted

	PARAMETER	TEST C	ONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub>	Propagation delay time, low-to-high-level output					100	
t <sub>PHL</sub>	Propagation delay time, high-to-low-level output				79	100	
t <sub>sk(p)</sub>	Pulse skew ( t <sub>PHL</sub> - t <sub>PLH</sub>  )	$V_{ID} = -1.5 \text{ V to}$ $C_L = 15 \text{ pF, Se}$	1.5 V, ee Figure 8		4	10	ns
t <sub>r</sub>	Output signal rise time	о <u>г</u> р. , о			1.5	3	
t <sub>f</sub>	Output signal fall time					3	
	Output disable time to high level		DE at 5 V, See Figure 9		5	50	ns
t <sub>PZH</sub>	Output disable time to high level	From standby	DE at 5 V, See Figure 9		1.6	3.5	μs
t <sub>PHZ</sub>	Output enable time from high level		DE at 5 V, See Figure 9		5	50	ns
	Output disable time to law level		DE at 0 V, See Figure 9		10	50	ns
t <sub>PZL</sub>	Output disable time to low level	From standby	DE at 5 V, See Figure 9		1.7	3.5	μs
t <sub>PLZ</sub>	Output enable time from low level		DE at 5 V, See Figure 9		8	50	ns



#### PARAMETER MEASUREMENT INFORMATION

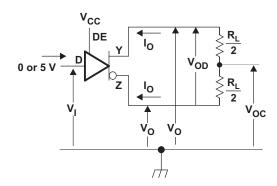


Figure 1. Driver V<sub>OD</sub> Test Circuit and Current Definitions

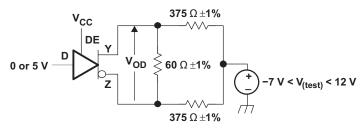


Figure 2. Driver V<sub>OD</sub> With Common-Mode Loading Test Circuit

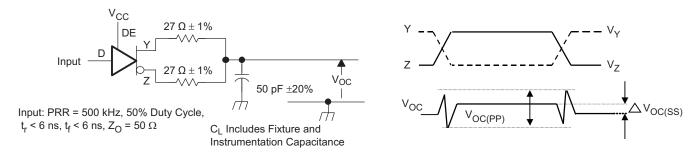


Figure 3. Test Circuit and Definitions for the Driver Common-Mode Output Voltage

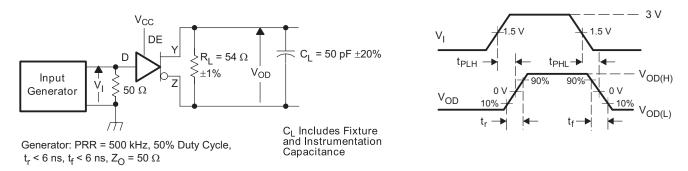


Figure 4. Driver Switching Test Circuit and Voltage Waveforms



#### PARAMETER MEASUREMENT INFORMATION (continued)

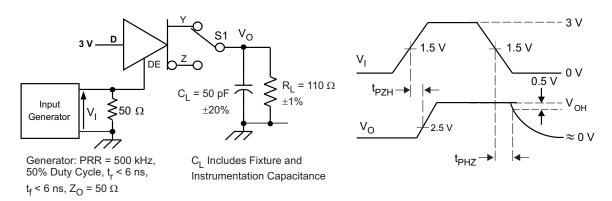


Figure 5. Driver High-Level Output Enable and Disable Time Test Circuit and Voltage Waveforms

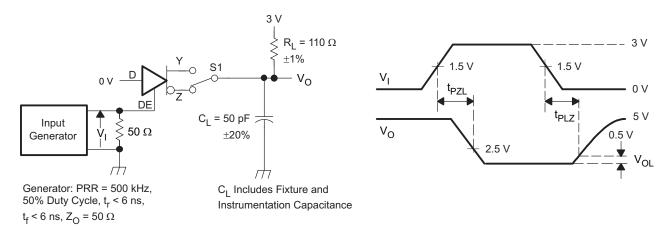


Figure 6. Driver Low-Level Output Enable and Disable Time Test Circuit and Voltage Waveforms

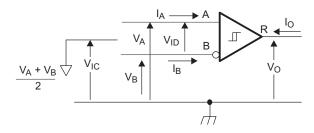


Figure 7. Receiver Voltage and Current Definitions

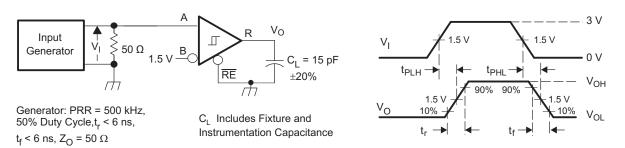


Figure 8. Receiver Switching Test Circuit and Voltage Waveforms



#### PARAMETER MEASUREMENT INFORMATION (continued)

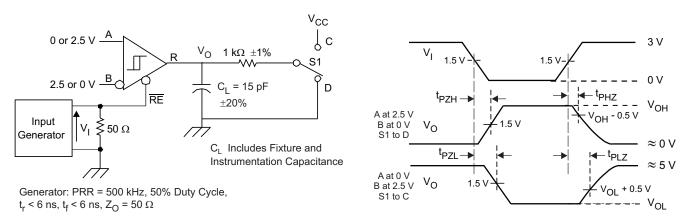
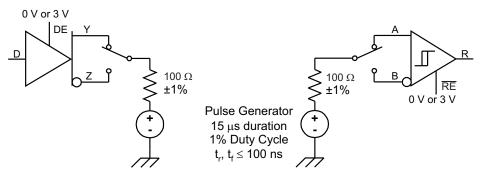


Figure 9. Receiver Enable and Disable Test Circuit and Voltage Waveforms



A. This test is conducted to test survivability only. Data stability at the R output is not specified.

Figure 10. Transient Overvoltage Test Circuit



#### **DEVICE INFORMATION**

#### **FUNCTION TABLES**

#### DRIVER<sup>(1)</sup>

INPUT	Enable	OUTPUTS		
D	DE	Y	Z	
Н	Н	Н	L	
L	Н	L	Н	
Х	L	Z	Z	
Open	Н	Н	L	

(1) H = high level, L = low level, Z = high impedance, X = irrelevant, ? = indeterminate

#### RECEIVER(1)

DIFFERENTIAL INPUTS $V_{ID} = V_{(A)} - V_{(B)}$	ENABLE RE	OUTPUT R
$V_{ID} \leq -0.2 V$	L	L
$-0.2 \text{ V} < \text{V}_{\text{ID}} < -0.01 \text{ V}$	L	?
-0.01 V ≤ V <sub>ID</sub>	L	Н
X	Н	Z
Open Circuit	L	Н
BUS Idle	L	Н
Short Circuit	L	Н

(1) H = high level, L = low level, Z = high impedance, X = irrelevant, ? = indeterminate

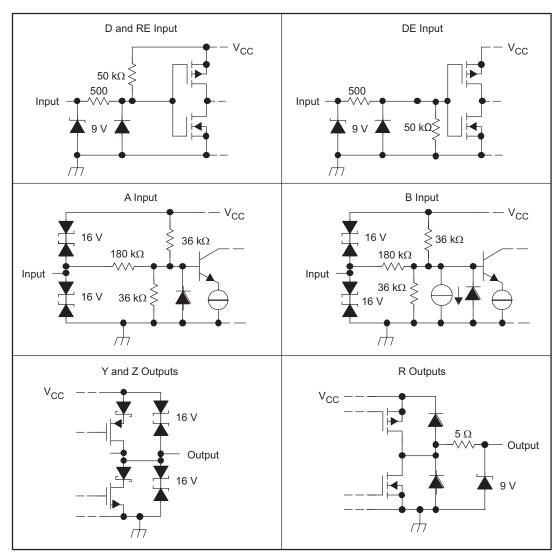
#### **DEVICE ELECTRICAL CHARACTERISTICS**

over operating free-air temperature range (unless otherwise noted)

	PARAMETERS	TEST CONDITIONS	MIN	TYP	MAX	UNIT
P <sub>(AVG)</sub>	Average power dissipation	$R_L$ = 60 $\Omega$ , Input to D a 500-kHz 50% duty cycle square-wave	85	109	136	mW



## **Equivalent Input and Output Schematic Diagrams**





#### **TYPICAL CHARACTERISTICS**

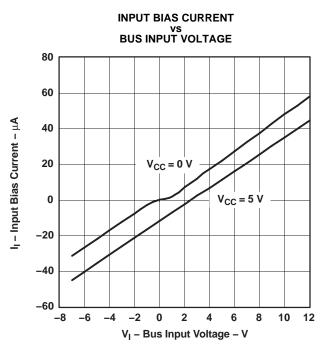
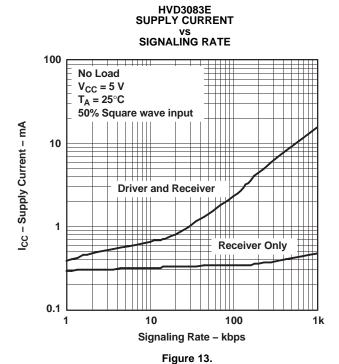


Figure 11.



HVD3080E SUPPLY CURRENT VS SIGNALING RATE

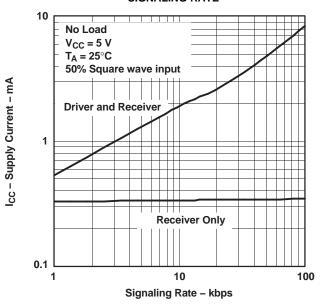


Figure 12.

#### HVD3086E SUPPLY CURRENT VS SIGNALING RATE

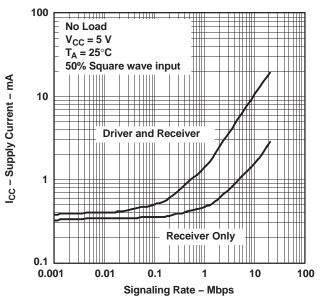
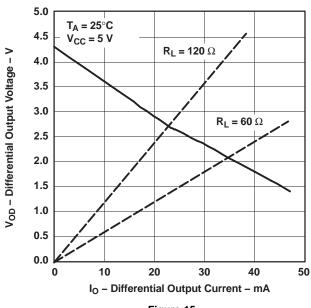


Figure 14.



#### **TYPICAL CHARACTERISTICS (continued)**

# DIFFERENTIAL OUTPUT VOLTAGE VS DIFFERENTIAL OUTPUT CURRENT



#### Figure 15.

# RECEIVER OUTPUT VOLTAGE VS DIFFERENTIAL INPUT VOLTAGE

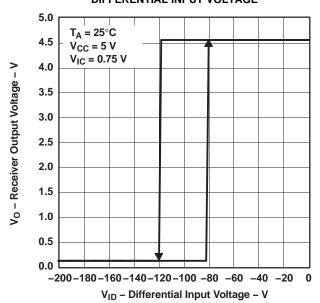


Figure 16.







Ch	Changes from A Revision (December 2006) to B Revision				
•	Changed V <sub>OH</sub> + 0.5 V to V <sub>OH</sub> - 0.5 V in Figure 9		8		

#### PACKAGE OPTION ADDENDUM



.com 29-Mar-2007

#### **PACKAGING INFORMATION**

Orderable Device	Status <sup>(1)</sup>	Package Type	Package Drawing	Pins	Package Qty	e Eco Plan <sup>(2)</sup>	Lead/Ball Finish	MSL Peak Temp (3)
SN65HVD3080EDGS	ACTIVE	MSOP	DGS	10	80	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
SN65HVD3080EDGSG4	ACTIVE	MSOP	DGS	10	80	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
SN65HVD3080EDGSR	ACTIVE	MSOP	DGS	10	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
SN65HVD3080EDGSRG4	ACTIVE	MSOP	DGS	10	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
SN65HVD3083EDGS	ACTIVE	MSOP	DGS	10	80	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
SN65HVD3083EDGSG4	ACTIVE	MSOP	DGS	10	80	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
SN65HVD3083EDGSR	ACTIVE	MSOP	DGS	10	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
SN65HVD3083EDGSRG4	ACTIVE	MSOP	DGS	10	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
SN65HVD3086EDGS	ACTIVE	MSOP	DGS	10	80	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
SN65HVD3086EDGSG4	ACTIVE	MSOP	DGS	10	80	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
SN65HVD3086EDGSR	ACTIVE	MSOP	DGS	10	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
SN65HVD3086EDGSRG4	ACTIVE	MSOP	DGS	10	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR

<sup>(1)</sup> The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND**: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

**Green (RoHS & no Sb/Br):** TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.



## **PACKAGE OPTION ADDENDUM**

29-Mar-2007

In no event shall TI's liabil	lity arising out of such inform	nation exceed the total n	urchase price of the TL	part(s) at issue in this o	document sold by T
to Customer on an annual	lity arising out of such inform I basis.	lation exceed the total p	urchase price of the 11 p	oant(s) at issue in this t	occument sold by T

## DGS (S-PDSO-G10)

### PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion.
- D. Falls within JEDEC MO-187 variation BA.



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